

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No.: 10/565,034 Confirmation No.: 7151
Applicant(s): Jean-Luc ROUVIERE, et al.
Filed: June 8, 2006
Art Unit: 2855
Examiner: Max H. NOORI
Title: METHOD FOR MEASURING PHYSICAL
PARAMETERS OF AT LEAST ONE
MICROMETRIC OR NANOMETRIC
DIMENSIONAL PHASE IN A COMPOSITE SYSTEM

Docket No.: 033339/306516
Customer No.: 00826

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT UNDER 37 C.F.R. § 1.121

Sir:

In response to the Office Action dated November 9, 2007, please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims beginning on page 2 of this paper.

Remarks/Arguments begin on page 9 of this paper.